In-situ hard x-ray microscopy of self-assembly in colloidal suspensions

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This supplementary information provides extended schematic representation of the μradXRD and theTXM setups and intensity profiles of the diffraction patterns in Figs 3-8 of the main text.

Fig. S1

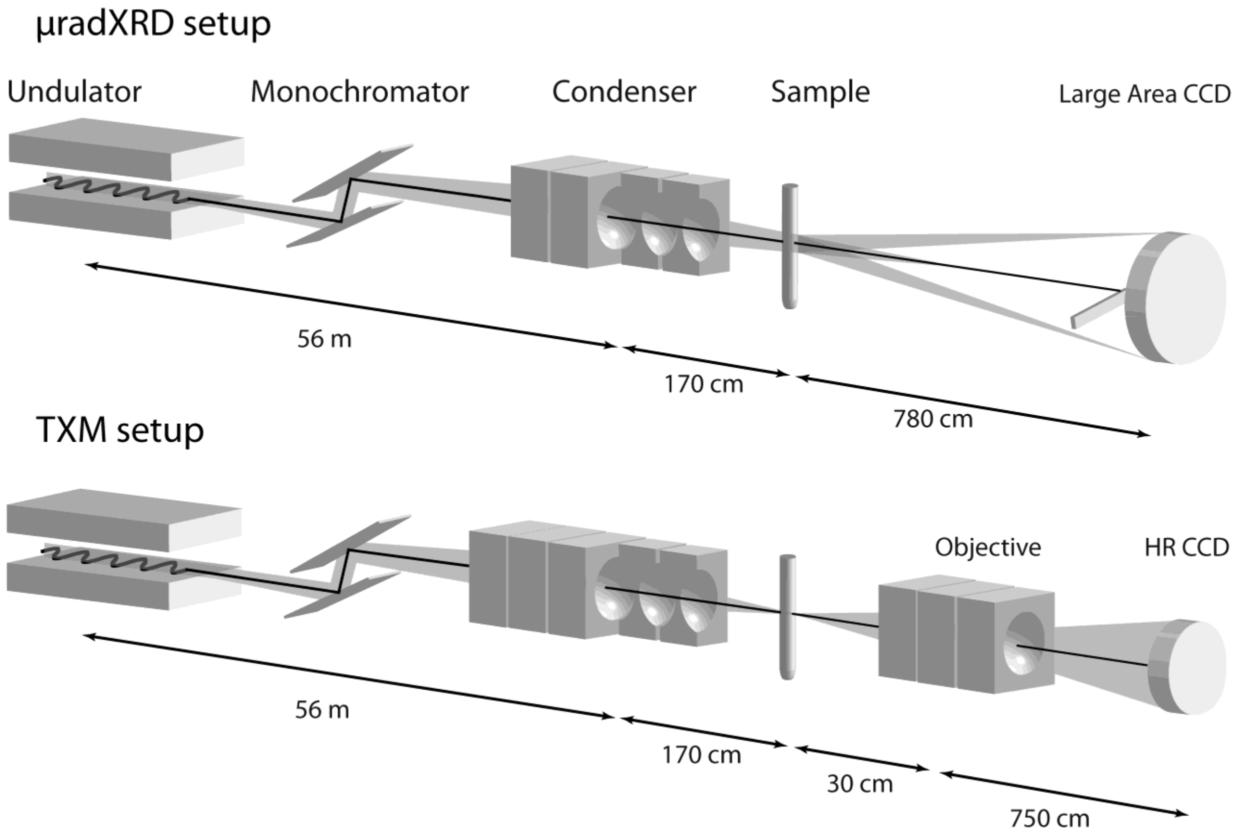

Fig. S2. *I*(*q*) profiles corresponding to Fig. 3A. Red squares correspond to vertical cut of the 2D pattern, green circles to horizontal cut.

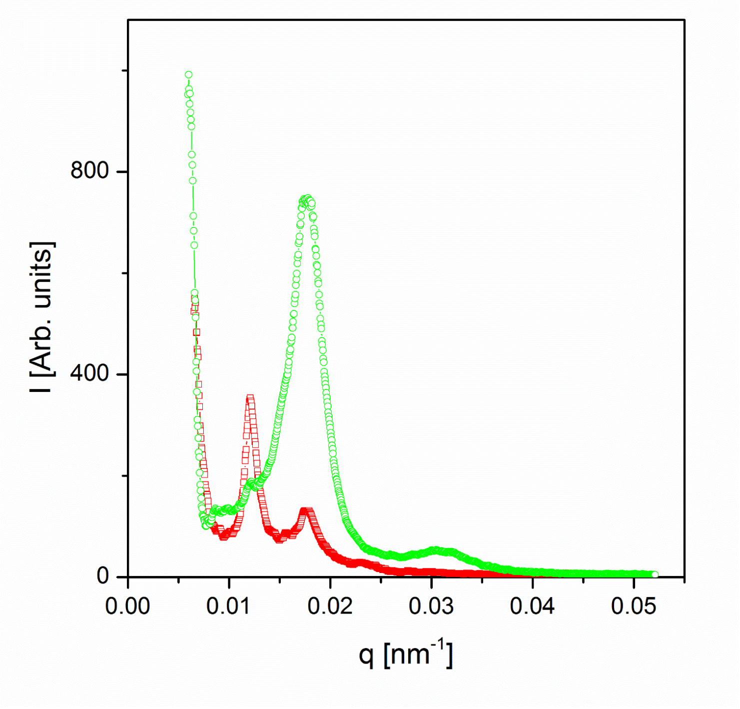

Fig. S3. I(q) profiles corresponding to Fig. 4A. Red squares is a cut of the 2D pattern through peaks originating from the smectic ordering in the system. Green circles is a cut through the broad peak.

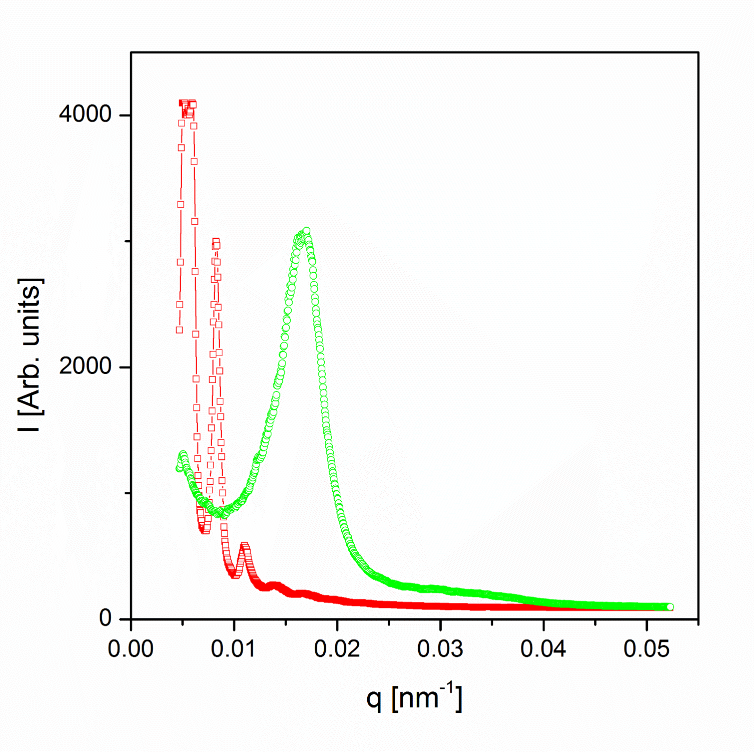

Fig. S4. *I*(*q*) profiles corresponding to Fig. 5A. Red squares correspond to the horizontal cut, green circles to the vertical cut.

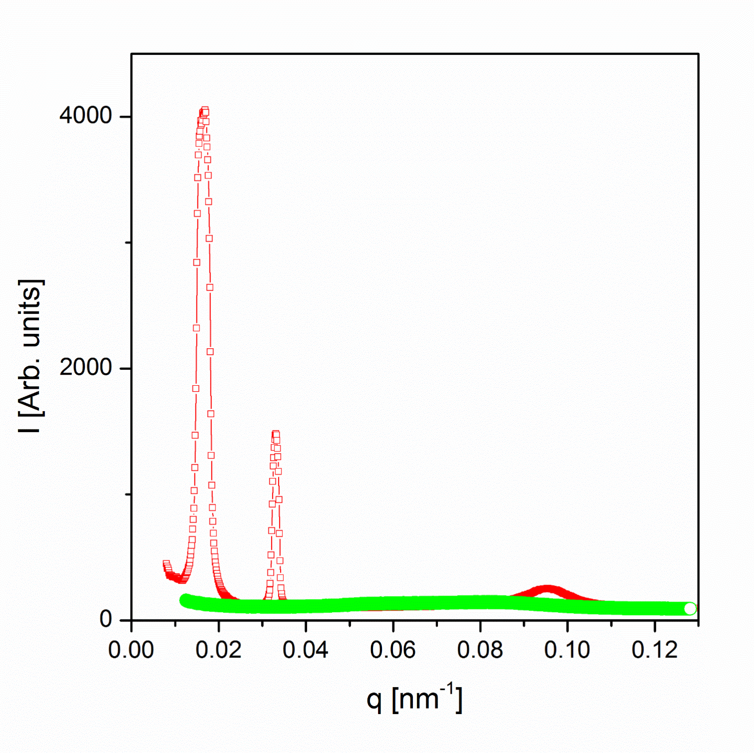

Fig. S5. I(q) profiles corresponding to Fig. 6A. Red squares is a cut through horizontal peaks, green circles is a cut from vertical peaks. Blue triangles and orange stars are cuts through higher order peaks.

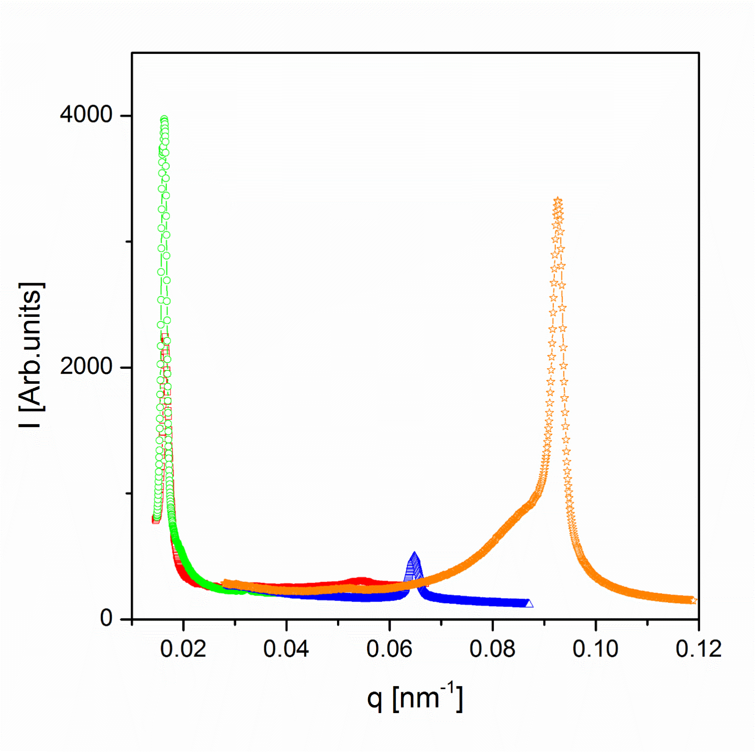

Fig. S6. I(q) profiles corresponding to Fig. 7A. Red squares is a cut through vertical peaks, green circles is a diagonal cut.

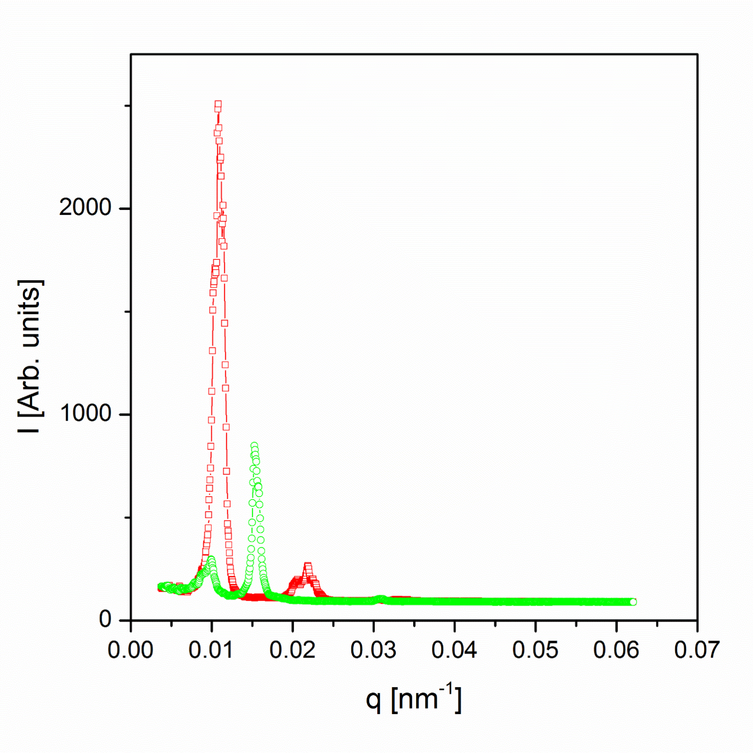

Fig. S7. I(q) profiles corresponding to Fig. 8A. Red squares is a cut through horizontal peaks, green circles is a cut from vertical peaks. Blue triangles and orange stars are cuts through higher order peaks. Blue triangles – diagonal cut.